

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office

IEEE Xplore®
 1 Million Documents
 1 Million Users
 Full-Text Search
 » Search Results

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)
Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **14** of **1049776** documents.
 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine **CNF** = Conference **STD** = Standard

1 Mechanism and device-to-device variation of leakage current in polysilicon thin film transistors

Wu, I.-W.; Lewis, A.G.; Huang, T.-Y.; Jackson, W.B.; Chiang, A.;
 Electron Devices Meeting, 1990. Technical Digest., International, 9-12 Dec. 1990
 Pages:867 - 870

[\[Abstract\]](#) [\[PDF Full-Text \(272 KB\)\]](#) IEEE CNF

2 Linear stochastic analysis of polluted insulator leakage current

Amarh, F.; Karady, G.G.; Sundararajan, R.;
 Power Delivery, IEEE Transactions on, Volume: 17, Issue: 4, Oct. 2002
 Pages:1063 - 1069

[\[Abstract\]](#) [\[PDF Full-Text \(477 KB\)\]](#) IEEE JNL

3 Level crossing analysis of leakage current envelope of polluted insulators

Amarh, F.; Karady, G.G.; Sundararajan, R.;
 Power Engineering Review, IEEE, Volume: 21, Issue: 8, Aug. 2001
 Pages:46 - 49

[\[Abstract\]](#) [\[PDF Full-Text \(296 KB\)\]](#) IEEE JNL

4 Reverse leakage current calculations for SiC Schottky contacts

Crofton, J.; Sriram, S.;
 Electron Devices, IEEE Transactions on, Volume: 43, Issue: 12, Dec. 1996
 Pages:2305 - 2307

[\[Abstract\]](#) [\[PDF Full-Text \(457 KB\)\]](#) IEEE JNL

5 Improved wafer-level spatial analysis for I_{DDQ} limit setting

Sabade, S.; Walker, D.M.H.;
 Test Conference, 2001. Proceedings. International, 30 Oct.-1 Nov. 2001
 Pages:82 - 91

[\[Abstract\]](#) [\[PDF Full-Text \(831 KB\)\]](#) IEEE CNF

6 On the calculation of the quasi-bound-state energies and lifetimes in inverted MOS structures with ultrathin oxides and its application to the direct tunneling current

Govoreanu, B.; Magnus, W.; Schoenmaker, W.; Van Houdt, J.; De Meyer, K.;
 Electron Devices, IEEE Transactions on, Volume: 51, Issue: 5, May 2004
 Pages:764 - 773

[\[Abstract\]](#) [\[PDF Full-Text \(416 KB\)\]](#) IEEE JNL

7 Influence of substrate current on hold-time characteristics of dynamic MOS IC's

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore®
 RELEASE 1.3

 Welcome
 United States Patent and Trademark Office

IEEE Xplore®
 1 Million Documents
 1 Million Users

» Search Results

[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Print Format

Your search matched **8** of **1049776** documents.
 A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering a new one in the text box.

(test vectors) <and> (probability) <and> (states)

Search

☐ Check to search within this result set
Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Built-in self test for C-testable ILA's

Gala, M.; Ross, D.; Watson, K.; Vasudevan, B.; Utama, P.;
 Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 14 , Issue: 11 , Nov. 1995
 Pages:1388 - 1398

[\[Abstract\]](#) [\[PDF Full-Text \(924 KB\)\]](#) IEEE JNL
2 On the fault coverage of interconnect diagnosis

Chen, X.T.; Meyer, F.J.; Lombardi, F.;
 VLSI Test Symposium, 1997., 15th IEEE , 27 April-1 May 1997
 Pages:101 - 107

[\[Abstract\]](#) [\[PDF Full-Text \(572 KB\)\]](#) IEEE CNF
3 Linear finite state machine for ID ILAs

Gala, M.M.R.; Utama, P.; Ross, D.E.; Watson, K.L.;
 VLSI Test Symposium, 1994. Proceedings., 12th IEEE , 25-28 April 1994
 Pages:325 - 332

[\[Abstract\]](#) [\[PDF Full-Text \(536 KB\)\]](#) IEEE CNF
4 Circuit behavior modeling and compact testing performance evaluation

Yih, J.-S.; Mazumder, P.;
 Solid-State Circuits, IEEE Journal of , Volume: 26 , Issue: 1 , Jan. 1991
 Pages:62 - 66

[\[Abstract\]](#) [\[PDF Full-Text \(384 KB\)\]](#) IEEE JNL
5 Performance of signature registers in the presence of correlated errors

Edirisooriya, G.; Robinson, J.P.;
 Computers and Digital Techniques, IEE Proceedings E [see also Computers and Digital Techniques, IEE Proceedings-], Volume: 139 , Issue: 5 , Sept. 1992
 Pages:393 - 400

[\[Abstract\]](#) [\[PDF Full-Text \(468 KB\)\]](#) IEEE JNL
6 Enhanced DO-RE-ME based defect level prediction using defect site aggregation-MPG-D

Dworak, J.; Grimaila, M.R.; Sooryong Lee; Wang, L.-C.; Mercer, M.R.;
 Test Conference, 2000. Proceedings. International , 3-5 Oct. 2000
 Pages:930 - 939

[\[Abstract\]](#) [\[PDF Full-Text \(760 KB\)\]](#) IEEE CNF
7 Generation of an ordered sequence of test vectors for single state transition faults in large